

**Notice of References Cited**

Application/Control No.

09/699,894

Applicant(s)/Patent Under

Reexamination

PADMANABHAN ET AL.

Examiner

Daniel A. Nolan

Art Unit

2655

Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,754,681	05-1998	Watanabe et al.	704/231
	B	US-5,737,723	04-1998	Riley et al.	704/243
	C	US-6,108,628	08-2000	Komori et al.	704/238
	D	US-5,263,097	11-1993	Katz et al.	706/10
	E	US-6,327,581	12-2001	Platt, John Carlton	706/12
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Chittineni et al ("On the Maximization of Divergence in Pattern Recognition - Correspondence", IEEE Transactions on Information Theory, September 1976)
	V	Guorong et al ("Bhattacharyya Distance Feature Selection", Proceedings of the 13th International Conference on Pattern Recognition, August 1996)
	W	Wang et al ("Classification Of Discrete Data With Feature Space Transformation", IEEE Transactions on Automatic Control, June 1979)
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.